

Product Specification

08-Aug-2017 Rev A

USB Type-C Connector

DESIGN OBJECTIVES

The product described in this document has not been fully tested to ensure conformance to the requirements outlined below. Therefore, TE makes no representation or warranty, express or implied, that the product will comply with these requirements. Further,

TE may change these requirements based on the results of additional testing and evaluation. Contact TE Engineering for further details.

1 Scope:

1.1 Contents

This specification covers the requirements for product performance, test methods and quality assurance provisions of TE Connectivity USB type C connector.

Applicable product description and part numbers are as shown in Appendix 1.

2. Applicable Documents:

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1 TE Connectivity Specification:

A. 109-1: Test Specification, General Requirements for Testing

B. 501-115141-2: Qualification Test Report.

2.2 Commercial Standard and Specification:

A. ANSI/EIA 364-C

B. Universal Serial Bus Type-C Connector and Cables Assemblies Compliance Document

3. Requirements:

3.1 Design and Construction:

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2 Materials:

A. Contact

Material: Copper alloy

B. Housing

Thermo Plastic, UL 94 V-0

C. Shell

Material: Stainless steel

3.3 Ratings:

A. Voltage Rating: 30V Max.

B. Current Rating:

(1). VBUS /GND pins: 1.25A/Pin Max.

(2). SBU1/SBU2: 1.0A/Pin Max.

(3). Signal pins contact: 0.25A Min.

C. Operation Temperature: -40°C to 85°C



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3.4 Performance Requirements and Test Descriptions:

The product shall be designed to meet the electrical, mechanical and environmental performance requirements specified in Fig.1. All tests shall be performed in the room temperature, unless otherwise specified.

Temperature:15°C \sim 35°C Humidity :25% \sim 85% R.H.

3.5 Test Requirements and Procedures Summary Table.1

Procedures	Requirements
EIA 364-18B	Visual inspection samples shall be free from defect such as damage, deformation, blister and burrs that are detrimental to the function and appearance.
EIA 364-23 The low level contact resistance (LLCR) measurement is made across the plug and receptacle mated contacts and does not include any internal paddle cards or substrates of the plug or receptacle. See Figure 1	40 mΩ (Max) initial for VBUS, GND and all other contacts. 50 mΩ Maximum after initial measurement.
	No discontinuities or shorts allowed.
EIA-364-20, Method B. Applicable to both receptacle and plug. 100VAC (rms) for 1 minute at sea level.	No break down shall occur when voltage is applied between adjacent contacts of unmated and mated connectors
EIA 364-21 Applicable to both receptacle and plug. Apply 500V DC Apply the above specified voltage between adjacent contacts for 1 minute.	>100 $M\Omega$ insulation resistance between adjacent contacts of unmated and mated connectors
EIA 364-70, Method 2. See USB Type C Compliancy Document Appendix C. A current of 5.0 A shall be applied collectively to VBUS pins (i.e., pins A4, A9, B4, and B9) and 1.25 A applied to the SBU1/SBU2 pin (i.e., A8/B8 of the plug connector) with the return path through the corresponding GND pins (i.e., pins A1, A12, B1, and B12). A minimum current of 0.25 A shall also be applied individually to all the other contacts. Allow to stabilize. Note: special T-rise test boards design per the guidelines in Appendix C of the USB Type C Compliancy Document are to	Temperature rise of the outside shell surface of the mated connector pair above the VBUS and GND contacts shall not exceed 30°C above ambient temperature.
	EIA 364-23 The low level contact resistance (LLCR) measurement is made across the plug and receptacle mated contacts and does not include any internal paddle cards or substrates of the plug or receptacle. See Figure 1 Measure at 20mV (max) open circuit at 100 mA See USB Type C Compliance Document Appendix E. EIA-364-20, Method B. Applicable to both receptacle and plug. 100VAC (rms) for 1 minute at sea level. EIA 364-21 Applicable to both receptacle and plug. Apply 500V DC Apply the above specified voltage between adjacent contacts for 1 minute. EIA 364-70, Method 2. See USB Type C Compliancy Document Appendix C. A current of 5.0 A shall be applied collectively to VBUS pins (i.e., pins A4, A9, B4, and B9) and 1.25 A applied to the SBU1/SBU2 pin (i.e., A8/B8 of the plug connector) with the return path through the corresponding GND pins (i.e., pins A1, A12, B1, and B12). A minimum current of 0.25 A shall also be applied individually to all the other contacts. Allow to stabilize. Note: special T-rise test boards design per the guidelines in

Table.1 (Cont.)

Test Item	Procedures	Requirements				
Mechanical						
Insertion Force	EIA-364-13 Maximum rate 12.5mm/min	Between 5N and 20N				
Extraction Force	EIA-364-13 Maximum rate 12.5mm/min	Initial: 8 N to 20 N; After test: 6 N to 20 N				
Durability	EIA 364-09 10,000 cycles	No evidence of physical damage				

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different P/N)

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Durability	EIA 364-09	No evidence of physical damage			
(Preconditioning) 50 cycles		No evidence of physical damage			
Reseating	Manually unplug/plug the connector. Perform 3 such cycles	No evidence of physical damage			
4-Axis Continuity Test	See USB Type C Compliancy Document Appendix D for detailed test fixtures and procedures. Plug and Receptacle: Subject the mating interface to the moments defined in USB Type C Compliancy Document Appendix D for at least 10 seconds.	No discontinuities greater than 1 microsecond duration in any of the four orientations tested.			
Table.1 (End.)					
Test Item	Procedures	Requirements			
Environmental		<u> </u>			
Temperature Life	EIA-364-17, Method A	Low level contact resistance meets spec before an			
	105°C without applied voltage for 120hrs	after the Temperature Life test.			
Temperature Life	EIA-364-17, Method A	Low level contact resistance meets spec before an			
(Preconditioning)	105°C, 72hrs	after the Temperature Life test.			
Thermal Shock	EIA-364-32, Method A, Condition I, duration A-4	No evidence of any physical damage.			
	(-55°-+85°C, 10 cycles)	Low level contact resistance meets spec before an			
		after the Thermal Shock test.			
Cyclic Temperature	· ·	No evidence of any physical damage.			
and Humidity	vibration.	Low level contact resistance meets spec before an			
	Exceptions per EIA-364-1000:	after the Thermal Shock test.			
	- Cycle between 25°C/80%RH and 65°C/50%RH.				
	- Ramp 0.5hr, dwell 1hr, dwell starts when conditions are stabilized.				
	- 24 cycles total				
	- Allowable variation ±3°C and ±3%RH				
Vibration	EIA-364-28, Condition VII-D, 15min in each of 3 mutually	No evidence of physical damages and no			
Vibration	perpendicular directions. Both mating halves should be	discontinuity longer than 1 microsecond.			
	fixed rigidly.	alsosmand, ronger than 2 mereseena.			
	(Power Spectral Density 0.02g ² /Hz, Overall rms 3.10g)				
Mixed Flowing Gas	EIA-364-65, class IIA, 112hrs unmated, 56hrs mated	No evidence of any physical damage.			
-	(168hrs total).	Low level contact resistance meets spec before an			
		after the Thermal Shock test.			
Thermal	Cycle the mated connector pair 10 times between 15°C	Low level contact resistance meets spec before an			
Disturbance	and 85°C.	after the test.			
	- ramp > 2°C/min				
	- dwell > 5 mins (ensure contacts reach temperature)				
	- Humidity not controlled				
Other					
Solderability	Category 3 Steam Age RMA Class 1 flux immerse in	Solderable area shall have a minimum of 95%			
	molten solder at a temperature of	solder coverage.			
	+255°C ± 5°C at rate of 25.4 mm ± 6.35 mm per				
	second.				
	Hold in solder for 5 +0/-0.5 seconds.				
	To include solder pins and mounting pads.				
	·				
Water Ingression	IEC 60529 – IPX8	1.5m/30 minutes, No water is allowed to ente			
(selective for		the enclosure. Use water contact detection			

NOTE: (1) Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Prequalification Test Sequence shown in table 2.

paper or color liquid.

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3.6 Product Qualification Test Sequence

Table.2

I able.2									
Test	A-1	A-2	A-3	A-4	A-7	B-1	B-6	C-11	C-2 ²
Visual Inspection	1,8	1,10	1,8	1,12	1,13	1,3	1,3	1,3	1,3
Low Level Contact Resistance	2,5,7	2,5,7,9	2,5,7	2,5,7,9,11	3,10				
Dielectric Withstanding Voltage					2,11				
Insulation Resistance					12				
Durability					7				
Durability (Preconditioning)	3	3	3	3					
Insertion Force					5,8				
Extraction Force					6,9				
Temperature Life	4			4					
Temperature Life (Preconditioning)			4						
Reseating	6	8		10	4				
Thermal Shock		4							
Cyclic Temperature and Humidity		6							
Vibration			6						
Mixed Flowing Gas				6					
Thermal Disturbance				8					
Current Rating							2		
4-Axis Continuity Test						2			
Solderability								2	
Water Ingression ²									2

Test Requirements and Test Sequence as per USB Type C Compliance Document.

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¹ Additional test, not part of USB Type C Compliance Requirements

² Additional test, selection item for water proof product.



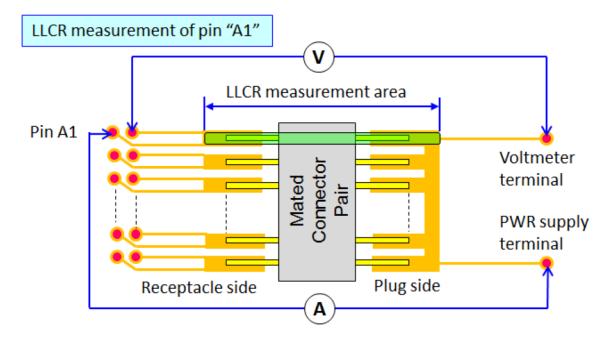


Figure 1: Typical Contact Resistance Measurement

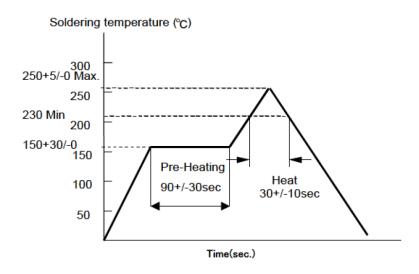


Figure 2. Recommended reflow temp profile

The applicable product descriptions and part numbers are as shown in Appendix.1.

Product Part No.	Description	Notes
2305018-2	USB type-c receptacle Dual Row SMT, on Board	IPX8
1-2305018-2	1-2305018-2 USB type-c receptacle Dual Row SMT, on Board	

Appendix.1

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Product Design Objective

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(Prepared by) Soldier Zhang Date

08-Aug-2017

(Checked by) Hapye Wu Date

08-Aug -2017

(Approved by) Simon Li Date

Date <u>08-Aug -2017</u>

LTR	REVISION RECORD	ECN	DR	CHK	APP	DATE
Α	RELEASE	-	S.ZH	H.W	S.L	08-Aug-2017

单击下面可查看定价,库存,交付和生命周期等信息

>>TE Connectivity(泰科)